Notice of References Cited Application/Control No. 10/648,841 Examiner Edgardo San Martin Applicant(s)/Patent Under Reexamination RALEIGH ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,039,559 A	06-1962	ELLSWORTH WILLIAM M	181/142
*	В	US-3,430,566 A	03-1969	PATTERSON EDWARD MERVYN	102/202.6
*	С	US-3,509,961 A	05-1970	FITCH HOMER L	181/115
*	D	US-4,108,272 A	08-1978	Paitson et al.	181/120
*	Ε	US-4,160,228 A	07-1979	Hix et al.	73/1.83
*	F	US-4,193,472 A	03-1980	Kirby, Robert A.	181/118
*	G	US-4,296,827 A	10-1981	Thigpen et al.	181/107
*	Τ	US-4,764,906 A	08-1988	Clements et al.	367/142
*	1	US-4,798,261 A	01-1989	Chelminski, Paul	181/120
*	J	US-4,811,815 A	03-1989	Meier et al.	181/120
*	К	US-5,864,517 A	01-1999	Hinkey et al.	367/145
*	٦	US-6,173,803 B1	01-2001	Barger, James Edwin	181/102
*	·M	US-2003/0037692 A1	02-2003	Liu, Liqing	102/301

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Nam	ne	Classification
	Ν	JP 11006698 A	01-1999	Japan .	NAKAMURA, SAT	тоѕні	F41B 06/00
	0						
	Ρ						
	Q						
	R						
	s						
	Т						744.4

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W .	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.